concentration occurs. This structural approach allows the probe to withstand high stress and offers a probe for a probe card with enhanced mechanical strength.

MEANS TO SOLVE THE PROBLEM

[0011] A probe for a probe card according to the present disclosure includes: a plurality of three-dimensional enclosed stress dispersion chambers embedded inside the probe, each chamber having ridges and vertices formed by inner wall surfaces.

EFFECT OF THE INVENTION

[0012] According to the probe for a probe card disclosed in this disclosure, even if the probe's thickness is reduced, a probe for a probe card with high mechanical strength can be provided by effectively dispersing the points of stress concentration.

BRIEF DESCRIPTION OF THE DRAWINGS

[0013] [FIG. 1] FIG. 1 is a schematic diagram illustrating the state of inspecting an electronic circuit using the probe card according to Embodiment 1.

[FIG. 2] FIG. 2 is a perspective view of the probe according to Embodiment 1.

[FIG. 3] FIG. 3 is a plan view showing the shapes of the three metallic layers composing the probe according to Embodiment 1.